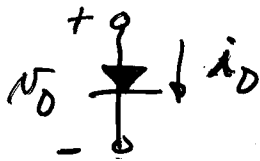


Review of ECE 3040

Two-terminal devices - Diode

Symbol -



$i_D = ac + dc$ (complex)
 $I_D = DC$
 $i_d = AC$

Model - (Large signal)

$$i_D = I_S \left[\exp\left(\frac{V_D}{mV_T}\right) - 1 \right]$$

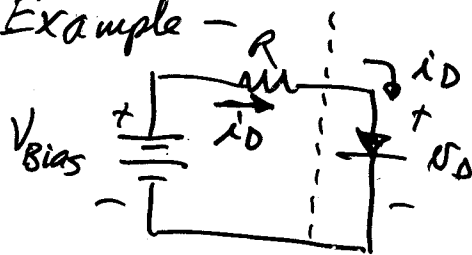
$I_S = \text{saturation current} = KT^3 \exp\left(-\frac{V_{G0}}{V_T}\right) \approx 10^{-15} \text{ A}$

$V_T = \frac{kT}{q} \approx 26 \text{ mV at } 300^\circ\text{K}$

$m = \text{linearity (slope of exponential)} \approx 1$

Application of the diode model

Example -



Find i_D & V_D

Given V_{Bias} & R & I_S & m .

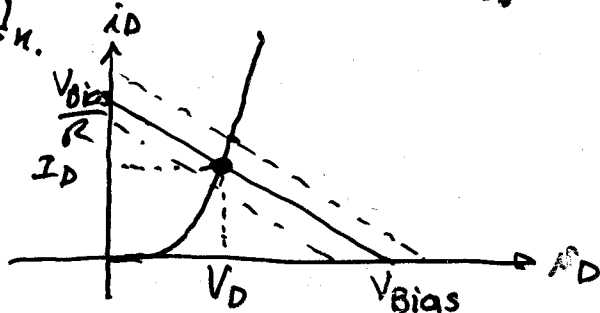
b.) Graphical

a.) Mathematical solution

$V_{Bias} = i_D R + V_D$

$$i_D = \frac{V_{Bias} - V_D}{R}$$

$$i_D \approx I_S \exp\left[\frac{V_D}{mV_T}\right], V_{Bias} > 0$$



Influence of Temperature

Forward biased diode -

$$i_D \approx I_S \exp\left(\frac{V_D}{nV_T}\right) \rightarrow V_D = nV_T \ln\left(\frac{i_D}{I_S}\right)$$

$$\frac{dV_D}{dT} = ? = \frac{V_D + 3V_T + V_{G0}}{T} \approx \underline{\underline{-2\text{mV}/^\circ\text{C}}} \quad (I_D \text{ is fixed})$$

Reverse biased diode - ($i_D \approx -I_S$)

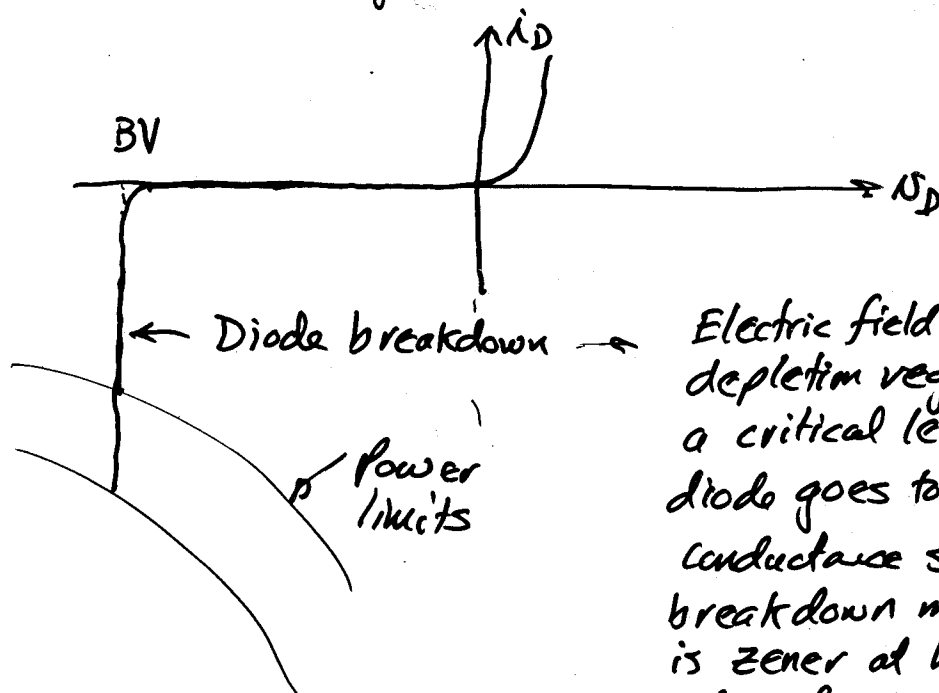
Temp. coefficient of I_S (i_D)

$$I_S = KT^3 \exp\left(\frac{-V_{G0}}{nV_T}\right) \quad (n=1)$$

$$\frac{1}{i_D} \frac{di_D}{dT} \rightarrow \frac{1}{I_S} \frac{dI_S}{dT} = \frac{3}{T} + \frac{V_{G0}}{TV_T}$$

$\rightarrow I_S$ doubles every 10°C increase

Breakdown Voltage of Diodes

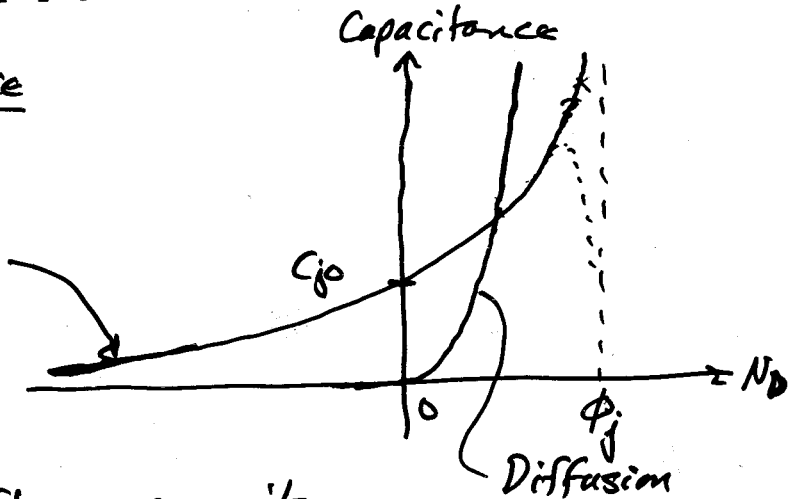


Electric field in the depletion region reaches a critical level and diode goes to a high conductance state. The breakdown mechanism is Zener at high doping and avalanche at lower doping.

Diode Capacitance

a.) Depletion

$$C_j = \frac{C_{j0}}{\sqrt{1 - \frac{V_D}{\phi_j}}}$$



b.) Diffusion

Current flow & capacitance

Diode Models

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